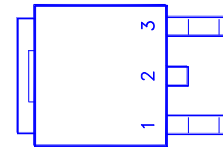
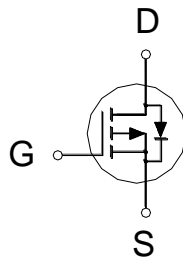


**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-30V	20mΩ	-35A



- 1. GATE
- 2. DRAIN
- 3. SOURCE



**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ °C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	-30	V
Gate-Source Voltage		$V_{GS}$	±25	V
Continuous Drain Current <sup>2</sup>	$T_C = 25\text{ °C}$	$I_D$	-35	A
	$T_C = 100\text{ °C}$		-22	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	-100	
Avalanche Current		$I_{AS}$	-26.5	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	35	mJ
Power Dissipation	$T_C = 25\text{ °C}$	$P_D$	46	W
	$T_C = 100\text{ °C}$		18	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.7	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Package limitation current is -30A.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25\text{ °C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-30			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1	-1.5	-3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 25V$			±100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V$			-1	μA
		$V_{DS} = -30V, V_{GS} = 0V, T_J = 125\text{ °C}$			-10	

Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = -10A$	16	20	mΩ	
		$V_{GS} = -4.5V, I_D = -10A$	23	30		
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -5V, I_D = -10A$	21		S	
<b>DYNAMIC</b>						
Input Capacitance <sup>4</sup>	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$	920	1150	1380	pF
Output Capacitance <sup>4</sup>	$C_{oss}$		123	154	184	
Reverse Transfer Capacitance <sup>4</sup>	$C_{rss}$		72	120	168	
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	3.8	7.5	11.3	Ω
Total Gate Charge <sup>2,4</sup>	$Q_g(V_{GS}=-10V)$	$V_{DS} = -15V, I_D = -10A$	17.6	24	26.4	nC
	$Q_g(V_{GS}=-4.5V)$		9.6	12	14.4	
Gate-Source Charge <sup>2,4</sup>	$Q_{gs}$		1.5	3	3.5	
Gate-Drain Charge <sup>2,4</sup>	$Q_{gd}$		3.2	5.3	7.4	
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$		$V_{DS} = -15V, I_D \cong -10A, V_{GS} = -10V, R_{GEN} = 6\Omega$		23	
Rise Time <sup>2</sup>	$t_r$			18		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			51		
Fall Time <sup>2</sup>	$t_f$			26		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25\text{ }^\circ\text{C}</math>)</b>						
Continuous Current <sup>3</sup>	$I_S$			-35	A	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = -10A, V_{GS} = 0V$		-1.3	V	
Reverse Recovery Time <sup>4</sup>	$t_{rr}$	$I_F = -10A, di_F/dt = 100A / \mu S$	5	10	15	nS
Reverse Recovery Charge <sup>4</sup>	$Q_{rr}$		1	2	4	nC

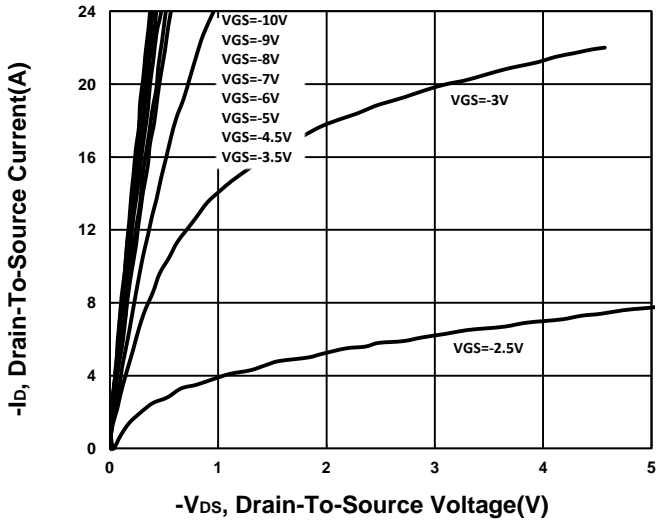
<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

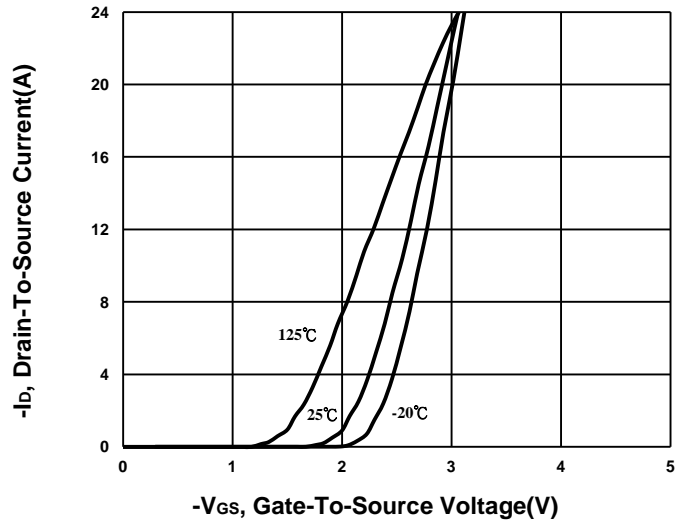
<sup>3</sup>Package limitation current is -30A.

<sup>4</sup>Guaranteed by design, not subject to production testing.

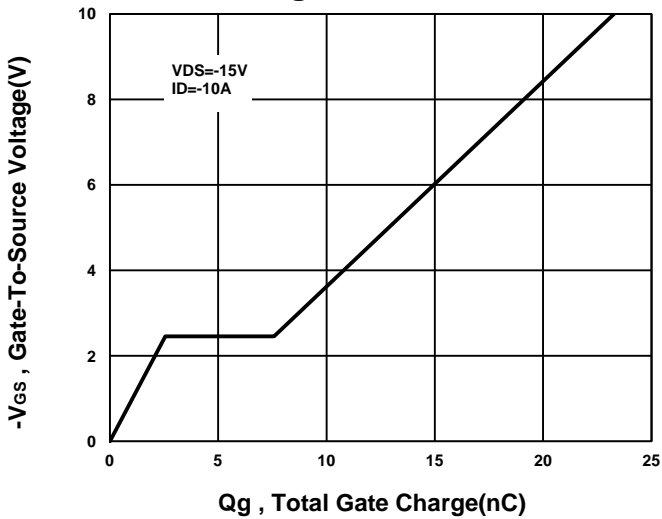
**Output Characteristics**



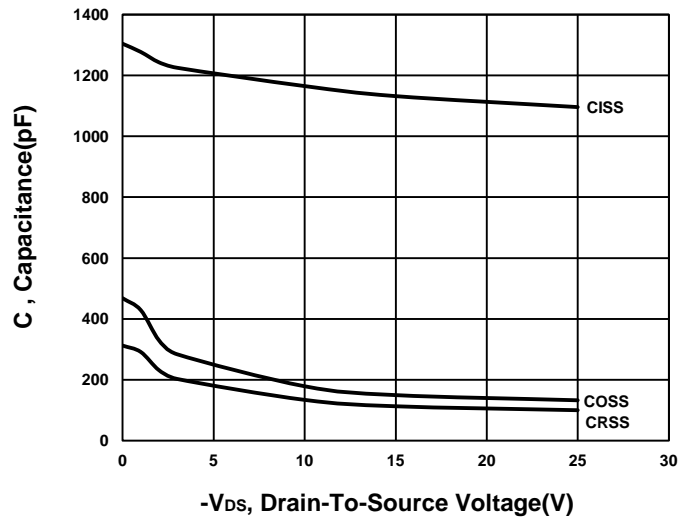
**Transfer Characteristics**



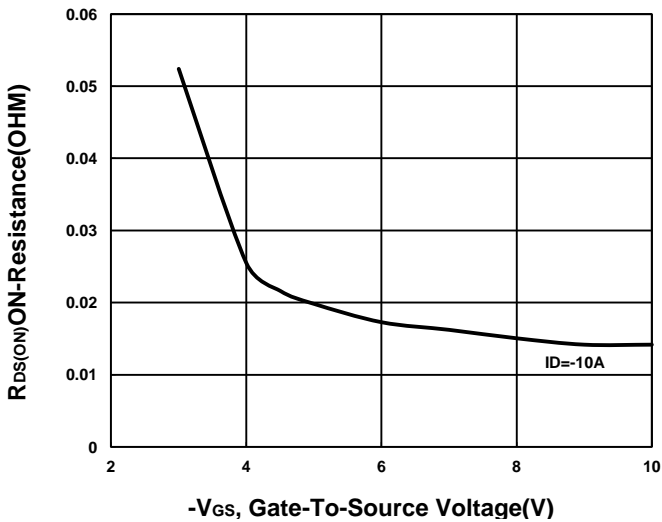
**Gate charge Characteristics**



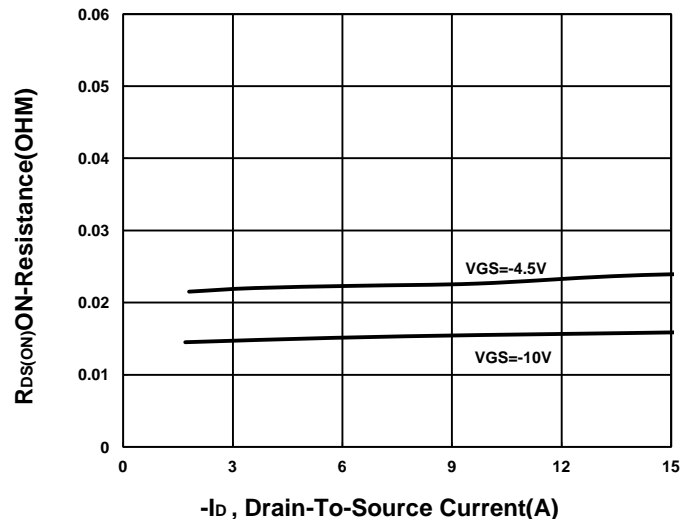
**Capacitance Characteristic**



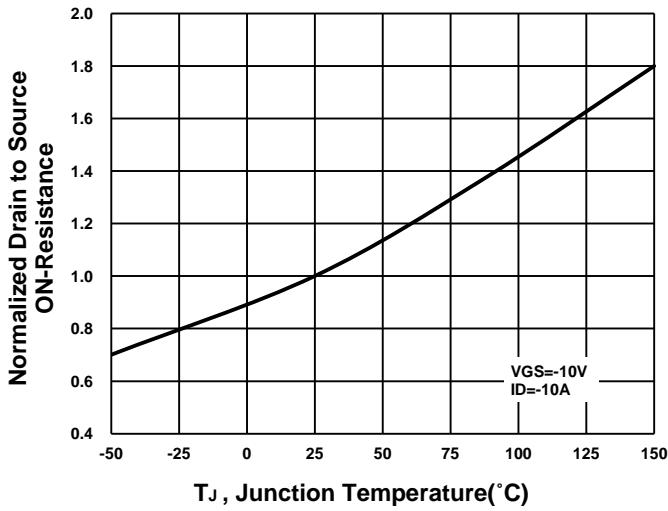
**On-Resistance VS Gate-To-Source**



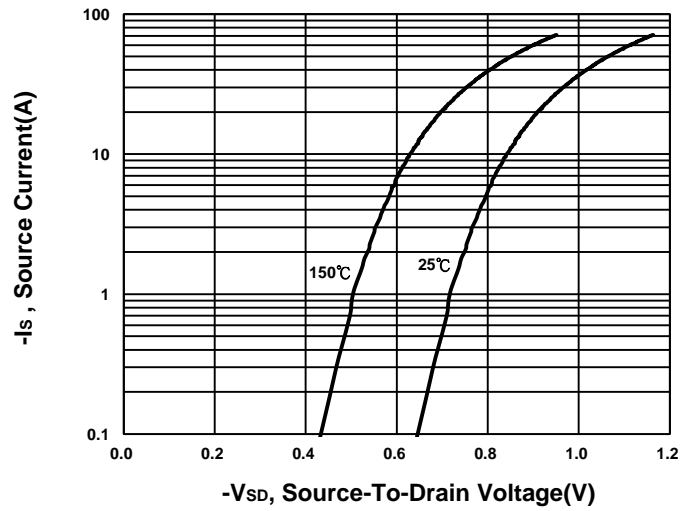
**On-Resistance VS Drain Current**



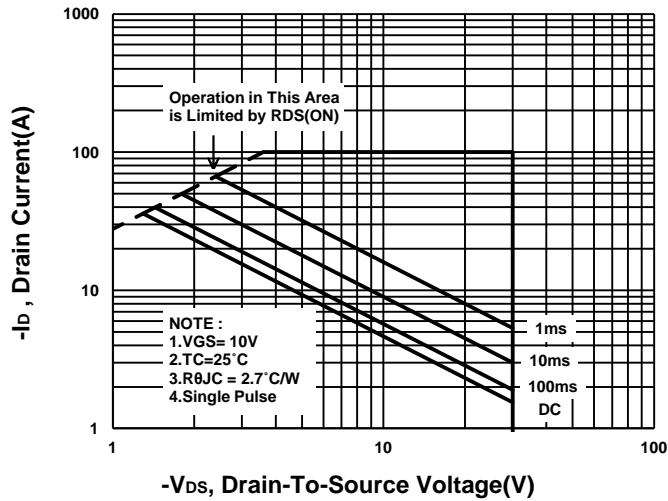
**On-Resistance VS Temperature**



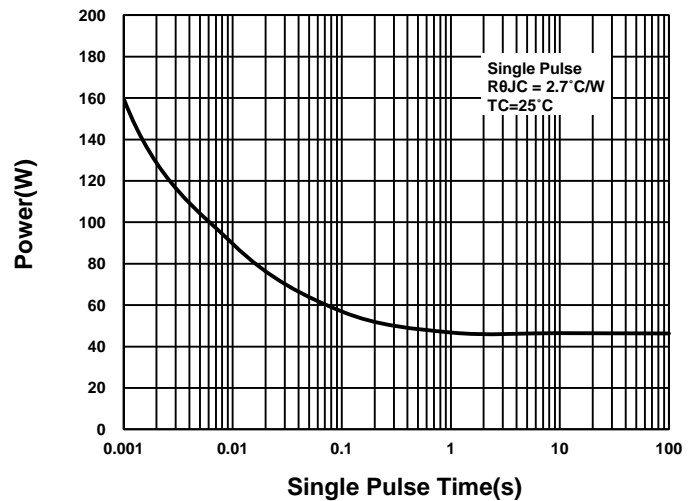
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

